

# GEN series GN412 

Differential 100 MS/s Input Card

## Special features

- 4 analog channels
- Balanced differential inputs
- $\quad \pm \mathbf{2 0 ~ m V}$ to $\pm \mathbf{1 0 0} \mathrm{V}$ input ranges
- User selectable digital Bessel IIR filters
- $100 \mathrm{MS} / \mathrm{s}$ sample rate
- 14/16 resolution
- $\quad 2$ GB memory
- Metal BNC inputs for each channel


## Differential 100 MS/s Input Card

For ultra fast signals, the $100 \mathrm{MS} / \mathrm{s}$ high speed digitizer card is equipped with four channels sampling at high speed.
The basic signal conditioner provides four channels of balanced differential voltage inputs from $\pm 20 \mathrm{mV}$ to $\pm 100 \mathrm{~V}$ Full Scale with full offset and auto-zero capability.
With selectable 6-pole Bessel anti-aliasing filtering and 14 bit resolution, these inputs turn the GEN series into an extremely fast transient recorder. Enhanced resolution mode increases input resolution to 16 bit at speeds of $10 \mathrm{MS} / \mathrm{s}$ or lower.
The inputs feature a fully differential amplifier offering good common mode rejection and enabling off ground measurements.

The on-board transient memory size is 1 GSample ( 2 GB ). The memory is shared among enabled channels. Each channel also features two set-points for trigger or alarm purposes. Extensive acquisition and trigger modes allow many different ways to capture valuable data even at the highest sample rates. All channels are synchronously sampled at full speed without multiplexing and almost immeasurable crosstalk. The model uses standard metal BNC connectors, whose shells are connected to ground. The inputs are $1 \mathrm{M} \Omega$ impedance and are compatible with probes.
The full transient and data recorder feature set of the GN412 together with the powerful Perception software eliminate the need to use separate data acquisition hardware or software.

## Capabilities Overview

| Model | GN412 |
| :--- | :--- |
| Maximum sample rate per channel | $100 \mathrm{MS} / \mathrm{s}$ |
| Memory per card | $2 \mathrm{~GB}(1 \mathrm{GS})$ |
| Analog channels | 4 |
| Anti-Alias filters | Fixed bandwidth analog AA-filter combined with a range of fixed bandwidth digital AA-filter |
| ADC resolution | 14 bit |
| Isolation | Not supported |
| Input type | Balanced differential |
| Passive voltage/current probes | Passive, single-ended voltage probes <br> Passive, differential matched isolated voltage probes <br> Sensors <br> TEDS <br> Real-time cycle based calculators <br> Real-time formula database calculators (option) <br> EtherCat® ${ }^{\circledR}$ output <br> Nigital Event/Timer/Counter <br> Standard data streaming (up to 200 MB/s) <br> Fast data streaming (up to 1 GB/s) <br> Slot width |

## Block Diagram



Figure 1.1: Block Diagram

Note The specifications listed are valid for cards that have been calibrated and are used in the same mainframe and slots as they were at the time of calibration. When the card is removed from its original location and placed in another slot and/or mainframe, the Offset error, Gain error and MSE specifications are expected to increase (up to double the original specification) due to thermal differences within the configurations. All specification are defined at $23^{\circ} \mathrm{C} \pm 2{ }^{\circ} \mathrm{C}$.

## Analog Input



Figure 1.2: Representative AC coupling response

| Impedance | 2 * $1 \mathrm{M} \Omega$ ( $\pm 2 \%$ ) // 23 pF ( $\pm 10 \%$ ) |  |  |
| :---: | :---: | :---: | :---: |
| Ranges | $\begin{aligned} & \pm 20 \mathrm{mV}, \pm 50 \mathrm{mV}, \pm 100 \mathrm{mV}, \pm 200 \mathrm{mV}, \pm 500 \mathrm{mV}, \pm 1 \mathrm{~V}, \pm 2 \mathrm{~V}, \pm 5 \mathrm{~V}, \pm 10 \mathrm{~V}, \pm 20 \mathrm{~V}, \pm 50 \mathrm{~V} \text { and } \\ & \pm 100 \mathrm{~V} \end{aligned}$ |  |  |
| Offset | $\begin{aligned} & \pm 50 \% \text { in } 1000 \text { steps ( } 0.1 \% \text { ) } \\ & \pm 100 \mathrm{~V} \text { range has fixed } 0 \% \text { offset } \end{aligned}$ |  |  |
| DC Offset error |  |  |  |
| Wideband | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Bessel filter | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Offset error drift | $\pm(50 \mathrm{ppm}+20 \mu \mathrm{~V}) /{ }^{\circ} \mathrm{C}\left( \pm(30 \mathrm{ppm}+12 \mu \mathrm{~V}) /{ }^{\circ} \mathrm{F}\right)$ |  |  |
| DC Gain error |  |  |  |
| Wideband | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Bessel filter | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Gain error drift | $\pm 100 \mathrm{ppm} /{ }^{\circ} \mathrm{C}\left( \pm 60 \mathrm{ppm} /{ }^{\circ} \mathrm{F}\right)$ |  |  |
| Maximum static error (MSE) |  |  |  |
| Wideband | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Bessel filter | $0.1 \%$ of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| RMS Noise (50 $\Omega$ terminated) |  |  |  |
| Wideband | 0.05\% of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Bessel filter | 0.05\% of Full Scale $\pm 100 \mu \mathrm{~V}$ |  |  |
| Common mode (referred to system ground) |  |  |  |
| Ranges | Less than or equal to $\pm 1 \mathrm{~V}$ | $\pm 2 \mathrm{~V}$ to $\pm 10 \mathrm{~V}$ | Larger than or equal to $\pm 20 \mathrm{~V}$ |
| Rejection (CMR) | $\geq 70 \mathrm{~dB}$ | $\geq 60 \mathrm{~dB}$ | $\geq 60 \mathrm{~dB}$ |
| Maximum common mode voltage | 4 V DC | 40 V DC | 250 V DC |


| Analog Input |  |
| :---: | :--- |
| Input overload protection | The activation of the overvoltage protection system results in a reduced input impedance. <br> The overvoltage protection is not active for as long as the input voltage remains less than 200\% of the <br> Selected input range or 250 V , whichever value is the smallest. |
| Maximum nondestructive voltage change | $\pm 125 \mathrm{~V} \mathrm{DC;}$; Ranges $\leq \pm 1 \mathrm{~V}$ <br> $\pm 250 \mathrm{~V} \mathrm{DC;} \mathrm{Ranges} \mathrm{>} \pm 1 \mathrm{~V}$ |
| Overload recovery time | Restored to $0.1 \%$ accuracy in less than 40 ns after $200 \%$ overload <br> Restored to $10 \%$ accuracy in less than 20 ns after 200\% overload |


| Analog to Digital Conversion |  |
| :--- | :--- |
| Sample rate per channel | $1 \mathrm{~S} / \mathrm{s}$ to $100 \mathrm{MS} / \mathrm{s}$ |
| ADC resolution; one ADC per channel | 14 bit |
| ADC Type | CMOS pipelined multistep converter, LTC2254 |
| Time base accuracy | Defined by mainframe: $\pm 3.5$ ppm ${ }^{(1)}$; aging after 10 years $\pm 10 \mathrm{ppm}$ |
| Binary sample rate | Not supported |
| Maximum binary sample rate | $\mathrm{N} / \mathrm{A}$ |
| External time base sample rate | $0 \mathrm{~S} / \mathrm{s}$ to $10 \mathrm{MS} / \mathrm{s}$ |
| External time base level | TTL |
| External time base minimum pulse width | 50 ns |

(1) Mainframes using Interface/Controller modules shipped before 2012: $\pm 30 \mathrm{ppm}$

## Anti-Alias Filters

Using different filter selections (Wideband/Bessel/Bessel IIR) or different filter bandwidths can result in phase mismatches between channels.


Figure 1.3: Combined analog and digital anti-alias filter block diagram
Anti-aliasing is prevented by a steep, fixed frequency analog anti-alias filter in front of the Analog to Digital Converter (ADC). The ADC always samples at a fixed sample rate. The fixed sample rate of the ADC avoids the need for different analog anti-alias filter frequencies. Directly behind the ADC, the high precision digital filter is used as anti-alias protection before the digital downsampling to the desired user sample rate is performed. The digital filter supports a range of fixed bandwidth anti-alias filters. Compared to analog anti-alias filters, the programmable digital filter offers additional benefits like higher order filter with steep roll-off, a larger selection of filter characteristics, noisefree digital output and no additional phase shifts between channels that use the same filter settings.

| Wideband | When wideband is selected, there is neither an analog anti-alias filter nor any digital filter <br> in the signal path. Therefore, there is no anti-alias protection when wideband is selected. <br> Wideband should not be used if working in a frequency domain with recorded data. <br> Using wideband, enhanced resolution is not supported at lower sample rates. |
| :--- | :--- |
| Bessel (Fc @-3 dB) | This analog Bessel filter can be used to reduce the higher bandwidth signals, but is also <br> used to prevent aliasing at the 100 and 50 MS/s sample rates. For lower sample rates, the <br> digital Bessel IIR filter must be used to prevent aliasing. Bessel filters are typically used <br> when looking at signals in the time domain. They are best used for measuring transient <br> signals or sharp edge signals like square waves or step responses. <br> Using the Bessel filter, enhanced resolution is not supported at lower sample rates. |
| Bessel IIR (Fc @-3 dB) | When Bessel IIR filter is selected, this is always a combination of an analog Bessel anti- <br> alias filter and a digital Bessel IIR filter to prevent aliasing at lower sample rates. This can <br> only be used for sample rates up to 50 MS/s. Bessel filters are typically used when looking <br> at signals in the time domain. They are best used for measuring transient signals or sharp <br> edge signals like square waves or step responses. <br> Enhanced resolution is supported by using over sampling combined with a digital filter at <br> the following sample rates: 15 bit resolution at 25 MS/s and lower, 16 bit resolution at <br> 10 MS/s and lower. |

## Wideband (No Anti-Alias Protection)

When wideband is selected, there is neither an analog anti-alias filter nor any digital filter in the signal path. Therefore, there is no anti-alias protection when wideband is selected.





Figure 1.4: Representative Wideband examples
(1) Measured using Fluke 5700A and 5820A calibrators, DC normalized

## Bessel Filter (Analog Anti-Alias)



Figure 1.5: Bessel Filter




Figure 1.6: Representative Bessel examples
(1) Measured using Fluke 5700A and 5820A calibrators, DC normalized

## Bessel IIR Filter (Digital Anti-Alias)



Figure 1.7: Digital Bessel IIR Filter
When Bessel IIR filter is selected, this is always a combination of the analog Bessel anti-alias filter and a digital Bessel IIR filter.

| Analog anti-aliasing filter bandwidth | $10 \mathrm{MHz} \pm 1 \mathrm{MHz}(-3 \mathrm{~dB})$ |
| :---: | :---: |
| Analog anti-aliasing filter characteristic | 6-pole Bessel, optimal step response |
| Bessel IIR filter characteristic | 8-pole Bessel style IIR |
| Bessel IIR filter user selection | User selectable fixed frequencies. If anti-aliasing must be prevented, care must be taken to adapt the selected filter frequency when the sample rate is changed. |
| Bessel IIR filter bandwidth ( $\omega \mathrm{c}$ ) | $50 \mathrm{kHz}, 100 \mathrm{kHz}, 125 \mathrm{kHz}, 200 \mathrm{kHz}, 250 \mathrm{kHz}, 400 \mathrm{kHz}, 500 \mathrm{kHz}, 1 \mathrm{MHz}, 1.25 \mathrm{MHz}, 2 \mathrm{MHz}$, $2.5 \mathrm{MHz}, 4 \mathrm{MHz}, 5 \mathrm{MHz}$; fixed bandwidth selections |
| Bessel IIR 0.1 dB passband flatness ( $\omega p$ ) ${ }^{(1)}$ | DC to 250 kHz @ $\omega \mathrm{c}=5 \mathrm{MHz}$ |
| Bessel IIR filter stop band attenuation (סs) | 60 dB |
| Bessel IIR filter roll-off | $48 \mathrm{~dB} /$ Octave |






Figure 1.8: Representative Bessel IIR examples
(1) Measured using Fluke 5700A and 5820A calibrators, DC normalized

## On-Board Memory

| Per card | 2 GB (1 GS) |
| :--- | :--- |
| Organization | Automatic distribution amongst enabled channels |
| Memory diagnostics | Automatic memory test when system is powered on but not recording |
| Storage sample size | 16 bits, 2 bytes/sample |

## Digital Events/Timer/Counter

| Digital event inputs | Not supported |
| :--- | :--- |
| Digital event outputs | Not supported |
| Timer/Counter | Not supported |

## Probe Power Output

| Connector type | LEMO ERD.0S.304.CLL |
| :--- | :--- |
| Mating connector type | LEMO FFA.0S.304.CLA.Cxx |
| Output power | 3.5 Watt |
| Output voltage | $>8 \mathrm{~V}$; Typically 8 V to 9 V |
| Maximum output current | $0.4 \mathrm{~A} ;$ Current limited and short circuit protected |

PIN Signal
PIN 1 - Reserved/not connected
PIN 2 - GND
PIN 3 - Reserved/not connected
PIN $4-+9 \mathrm{~V}$


Figure 1.9: Probe power connector output

## Triggering

| Channel trigger/qualifier | 1 per channel; fully independent per channel, software selectable either trigger or qualifier |
| :---: | :---: |
| Pre- and post-trigger length | 0 to full memory |
| Maximum trigger rate | 400 triggers per second |
| Manual trigger (Software) | Supported |
| External Trigger In |  |
| Selection per card | User selectable On/Off |
| Active edge | Rising/Falling mainframe selectable, identical for all cards |
| Minimum pulse width | 500 ns |
| Delay | $\pm 50 \mathrm{~ns}+$ maximum 1 sample period |
| Send to External Trigger Out | User can select to forward External Trigger In to the External Trigger Out BNC |
| External Trigger Out |  |
| Selection per card | User selectable On/Off |
| Active level | High/Low/Hold High; selectable per mainframe, identical for all cards |
| Pulse width | High/Low: $12.8 \mu \mathrm{~s}$ <br> Hold high: Active from first mainframe trigger to end of recording Pulse width created by mainframe |
| Delay | User selectable ( $3 \mu \mathrm{~s}$ to $516 \mu \mathrm{~s}$ ) $\pm 1 \mu \mathrm{~s}+$ maximum 1 sample period (requires Perception V 6.50 or higher). The default of $516 \mu \mathrm{~s}$ is compatible with standard behavior. Minimum selectable delay is the smallest delay available for all acquisition cards used within the mainframe |
| Cross channel triggering |  |
| Measurement channels | Logical OR of triggers from all measured signals Logical AND of qualifiers from all measured signals |
| Calculated channels | Logical OR of triggers from all calculated signals (RTC and RT-FDB) Logical AND of qualifiers from all calculated signals (RTC and RT-FDB) |
| Analog channel trigger levels |  |
| Levels | Maximum 2 level detectors |
| Resolution | 16 bit (0.0015\%); for each level |
| Direction | Rising/Falling; Single direction control for both levels based on selected mode |
| Hysteresis | 0.1 to 100\% of Full Scale; defines the trigger sensitivity |
| Pulse detection/rejection | Disable/Detect/Reject software selectable. Maximum pulse width 65535 samples |
| dY/dT conversion | dY: 16 bit ( $0.0015 \%$ ) for both levels <br> dT: 1 to 1023 samples. dT setting shared for both levels |
| Analog channel trigger modes |  |
| Basic | POS or NEG crossing; single level |
| Dual level | One POS and one NEG crossing; Two individual levels, OR-ed |
| Window | Arm/trigger and a disarm level; Trigger on peak level changes in a uni-polar signal |
| Dual Window | Arm/trigger/disarm per level; Trigger on peak level changes in a bi-polar signal |
| Sequential | One arm and one trigger level; eliminate false triggering due to noise or hysteresis |
| Analog channel qualifier modes |  |
| Basic | Above or below level check. Enable/disable trigger with single level |
| Dual (level) | Outside or within bounds check. Enable/disable trigger with dual level |
| Trigger hold off | Disable channel trigger for 1 to 65535 samples after trigger detected Maximum hold off time depends on sample rate |
| Interval timer |  |
| Modes | Less than, trigger when rate is too low More than, trigger when rate is too high Between, trigger when rate between lower and upper limit Not between, trigger when rate is not between lower and upper limit |
| Interval timers | Start timer and width Timer |
| Timer value | 1 to 65535 samples |
| Event counter | Counted channel trigger events before card trigger is activated 1 to 256 trigger events |

## Alarm Output

| Selection per card | User selectable On/Off |
| :---: | :---: |
| Alarm modes | Basic or Dual |
| Basic | Above or below level check |
| Dual (level) | Outside or within bounds check |
| Alarm levels |  |
| Levels | Maximum 2 level detectors |
| Resolution | 16 bit (0.0015\%) for each level |
| Alarm output | Active during valid alarm condition, output supported through mainframe |
| Alarm output delay | $515 \mu \mathrm{~s} \pm 1 \mu \mathrm{~s}+$ maximum 1 sample period using decimal time base $503 \mu \mathrm{~s} \pm 1 \mu \mathrm{~s}+$ maximum 1 sample period using binary time base |

## Real-Time Analysis

StatStream ${ }^{\circledR}$
Patent Number : 7,868,886

Each channel includes real-time extraction of Maximum, Minimum, Mean, Peak-to-Peak, Standard Deviation and RMS values
Supports the real-time live scrolling and scoping of waveform displays and the real-time meters while recording
Supports fast displaying and zooming within extremely large recordings
Supports fast calculations of statistical channel information

## Acquisition Modes

| Single sweep | Triggered acquisition to on-board memory without sample rate limitations; for single <br> transients or intermittent phenomena. No aggregate sample rate limitations. |
| :--- | :--- |
| Multiple sweeps | Triggered acquisition to on-board memory without sample rate limitations; for repetitive <br> transients or intermittent phenomena. No aggregate sample rate limitations. |
| Slow-Fast Sweep | Identical to single sweep acquisition with additional support for fast sample rate switches <br> during the post-trigger segment of the slow rate single sweep settings. No aggregate sample <br> rate limitations. Slow-Fast Sweep is not supported by the RT-FDB calculators. |
| Continuous | Direct storage to PC or mainframe controlled hard disk without file size limitations; triggered <br> or un-triggered; for long duration recorder type applications. Aggregate sample rate <br> limitations depend on Ethernet speed, PC used and data storage media used. |
| Dual | Combination of Multiple sweeps and Continuous; recorder type streaming to hard disk with <br> simultaneously triggered sweeps in on-board memory. Aggregate sample rate limitations <br> depend on Ethernet speed, PC used and data storage media used. <br> In Dual mode the RT-FDB calculators sample based results are only calculated for the <br> sweep sections of the recorded data. Due to the asynchronous nature of cycle based results, <br> all cycle based results are continuously stored and used in both the sweep as well as the <br> continuous sections of the recording. |

## Recording Mode Details

|  | Single Sweep Multiple Sweeps Slow-Fast Sweep |  |  | Continuous |  |  | Dual Rate |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | Enabled channels |  |  | Enabled channels |  |  | Enabled channels |  |  |
|  | 1 Ch | 2 Ch | 4 Ch | 1 Ch | 2 Ch | 4 Ch | 1 Ch | 2 Ch | 4 Ch |
| Max. sweep memory | 980 MS | 490 MS | 235 MS |  | not us |  | 800 MS | 390 MS | 180 MS |
| Max. sweep sample rate | $100 \mathrm{MS} / \mathrm{s}$ |  |  | not used |  |  | $100 \mathrm{MS} / \mathrm{s}$ |  |  |
| Max. continuous FIFO |  | not used |  | 980 MS | 490 MS | 235 MS | 180 MS | 90 MS | 45 MS |
| Max. continuous sample rate | not used |  |  | $20 \mathrm{MS} / \mathrm{s}$ |  |  | Sweep sample rate / 2 Maximum $20 \mathrm{MS} / \mathrm{s}$ |  |  |
| Max. aggregate continuous streaming rate | not used |  |  | $20 \mathrm{MS} / \mathrm{s}$ $40 \mathrm{MB} / \mathrm{s}$ | $40 \mathrm{MS} / \mathrm{s}$ $80 \mathrm{MB} / \mathrm{s}$ | $\begin{gathered} \hline 80 \mathrm{MS} / \mathrm{s}^{(1)} \\ 160 \mathrm{MB} / \mathrm{s}^{(1)} \end{gathered}$ | $20 \mathrm{MS} / \mathrm{s}$ 40 MB/s | $40 \mathrm{MS} / \mathrm{s}$ $80 \mathrm{MB} / \mathrm{s}$ | $\begin{gathered} 80 \mathrm{MS} / \mathrm{s}^{(1)} \\ 160 \mathrm{MB} / \mathrm{s}^{(1)} \end{gathered}$ |

(1) Only mainframes with "fast data streaming" support can stream at this data rate continuously.

## Single Sweep

| Pre-trigger segment | $0 \%$ to $100 \%$ of selected sweep length <br> If trigger occurs before the pre-trigger segment is recorded, the pre-trigger segment is <br> truncated to recorded data only. |
| :--- | :--- |
| Delayed trigger | Maximum 1000 seconds after a trigger occurred. The sweep is recorded immediately after <br> a delayed trigger time with $100 \%$ post-trigger after this time point. |
| Sweep stretch | User selectable On/Off <br> When enabled, any new trigger event occurring in the post-trigger segment of the sweep <br> restarts the post-trigger length. If, upon the detection of a new trigger, the extended post- <br> trigger does not fit within the sweep memory, sweep stretch does not happen. The maximum <br> sweep stretch rate is 1 sweep stretch per 2.5 ms. |


| Multiple Sweeps |  |
| :--- | :--- |
| Pre-trigger segment | $0 \%$ to $100 \%$ of selected sweep length <br> If trigger occurs before the pre-trigger segment is recorded, the pre-trigger segment is <br> truncated to recorded data only. |
| Delayed trigger | Maximum 1000 seconds after a trigger occurred. The sweep is recorded immediately after <br> a delayed trigger time with 100\% post-trigger after this time point. |
| Maximum number of sweeps | 200000 per recording |
| Maximum sweep rate | 400 sweeps per second |
| Sweep re-arm time | Zero re-arm time, sweep rate limited to 1 sweep per 2.5 ms |
| Sweep stretch | User selectable On/Off <br> When enabled, any new trigger event occurring in the post-trigger segment of the sweep <br> restarts the post-trigger length. If, upon the detection of a new trigger, the extended post- <br> trigger does not fit within the sweep memory, sweep stretch does not happen. The maximum <br> sweep stretch rate is 1 sweep stretch per 2.5 ms. |
| Sweep storage | Sweep storage is started immediately after the trigger for this sweep has been detected. <br> Sweep memory becomes available for reuse as soon as storage of the entire sweep for all <br> enabled channels of this card has been completed. Sweeps are stored one by one, starting <br> with the first recorded sweep. |
| Sweep storage rate | Determined by the total number of selected channels and mainframes, mainframe type, <br> Ethernet speed, PC storage medium and other PC parameters. For details, please refer to <br> the mainframe datasheet. |
| Exceeding sweep storage rate | Trigger event markers are stored in a recording. No sweep data is stored. New sweep data <br> is recorded as soon as enough internal memory is available to capture a full sweep when <br> a trigger occurs. |

## Slow-Fast Sweep

| Maximum number of sweeps | 1 per recording |
| :--- | :--- |
| Maximum slow sample rate | Fast sample rate divided by two or $20 \mathrm{MS} / \mathrm{s}$ per channel, whichever is the smallest sample <br> rate |
| Maximum sample rate switches | 20, sample rate switching always stops when sweep ends |
| Minimum time between sample rate switches | 2.5 ms |

Continuous

| Continuous modes supported | Standard, Circular recording, Specified time and Stop on trigger |
| :--- | :--- |
| Standard | User starts and stops recording. Recording is stopped when the storage media is full |
| Circular recording | User specified recording history on storage media. All recorded data is stored on the storage <br> media as quickly as possible. As soon as the selected history time is reached, older recorded <br> data is overwritten. Recording can be stopped by the user or any system trigger. |
| Stop on trigger | Recording is stopped after the time specified or when the storage media is full |
| Recording is stopped after any system trigger or when the storage media is full |  |
| Continuous FIFO memory | Used by enabled channels to optimize the continuous streaming rate |
| Maximum recording time | Until storage media filled or user selected time or unlimited when using circular recording |
| Maximum aggregate streaming rate per | Determined by mainframe, Ethernet speed, PC storage medium and other PC parameters. <br> mainframe |
| For details, please refer to the mainframe datasheet |  |


| Dual |  |
| :---: | :---: |
| Dual Sweep Specification |  |
| Pre-trigger segment | $0 \%$ to $100 \%$ of selected sweep length <br> If trigger occurs before the pre-trigger segment is recorded, the pre-trigger segment is truncated to recorded data only. |
| Delayed trigger | Maximum 1000 seconds after a trigger occurred. The sweep is recorded immediately after a delayed trigger time with $100 \%$ post-trigger after this time point. |
| Maximum number of sweeps | 200000 per recording |
| Maximum sweep rate | 400 sweeps per second |
| Sweep re-arm time | Zero re-arm time, sweep rate limited to 1 sweep per 2.5 ms |
| Sweep stretch | User selectable On/Off <br> When enabled, any new trigger event occurring in the post-trigger segment of the sweep restarts the post-trigger length. If, upon the detection of a new trigger, the extended posttrigger does not fit within the sweep memory, sweep stretch does not happen. The maximum sweepstretch rate is 1 sweep stretch per 2.5 ms . |
| Sweep storage | In dual mode, the storage of the continuous data is prioritized above the storage of the sweep data. If enough storage rate is available, the sweep storage is started immediately after the trigger for this sweep has been detected. Sweep memory becomes available for reuse as soon as storage of the entire sweep for all enabled channels of this card has been completed. Sweeps are stored one by one, starting with the first recorded sweep. |
| Sweep storage rate | Determined by the continuous sample rate, total number of channels and mainframes, mainframe type, Ethernet speed, PC storage medium and other PC parameters. For details, please refer to mainframe datasheet. |
| Exceeding sweep storage rate | Continuous recorded data is not stopped, trigger event markers are stored in recording and no new sweep data is stored. A new sweep is recorded as soon as enough internal memory is available to capture a full sweep when a trigger occurs. |
| Dual Continuous Specifications |  |
| Continuous FIFO memory | Used by enabled channels to optimize the continuous streaming rate |
| Maximum recording time | Until storage media filled or user selected time |
| Maximum aggregate streaming rate per mainframe | Determined by mainframe, Ethernet speed, PC storage medium and other PC parameters. For details, please refer to the mainframe datasheet. <br> When the average aggregate streaming rate is exceeded, the sweep storage speed is automatically reduced to increase the aggregate streaming rate until the sweep storage is stopped completely. |
| Exceeding aggregate storage rate | When a streaming rate higher than the aggregate streaming rate of the system is selected, the continuous memory acts as a FIFO. As soon as this FIFO fills up, the recording is suspended (no data is recorded temporarily). During this period, the internal FIFO memory is transferred to the storage medium. When the internal memory (Continuous and Sweep memory) is completely empty, the recording is automatically resumed. User notifications are added to the recording file for post recording identification of storage overrun. |



Figure 1.10: Block diagram passive, single-ended voltage probe

| Isolation | Not supported |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Capacitive compensation range | 7 to 75 pF |  |  |  |
| DC In-accuracy | 2\% |  |  |  |
|  | G901 |  | G902 |  |
| Divide factors | 1:1 | 10:1 | 1:1 | 10:1 |
| Probe impedance (connected to channel) | $1 \mathrm{M} \Omega$ | $10 \mathrm{M} \Omega$ | $1 \mathrm{M} \Omega$ | $10 \mathrm{M} \Omega$ |
| - 3 dB Bandwidth | 12 MHz | 200 MHz | 6 MHz | 100 MHz |
| Maximum input voltage | 55 V RMS | 300 V RMS CAT II | 55 V RMS | 300 V RMS CAT II |
| Probe cable length | 1.2 m (3.9 ft) |  | 3 m (9.8 ft) |  |
| Probe weight | Typically 59 g (2.1 oz) |  | Typically $88 \mathrm{~g}(3.1 \mathrm{oz})$ |  |
| Original manufacturer's part number | PMK 869-923900 |  | PMK 869-924900 |  |
| Probe operating temperature range | $0^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(32{ }^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |  |  |  |



Figure 1.11: Probe and probe accessories

G903: Passive, Single-Ended Voltage Probe (Option, to be ordered separately)
To be used with single-ended amplifiers or with differential amplifiers in single-ended mode


Figure 1.12: Block diagram passive, single-ended voltage probe

| Isolation | Not supported |
| :---: | :---: |
| Capacitive compensation range | 7 to 45 pF |
| DC In-accuracy | 2\% |
| Divide factors | 100:1 |
| Probe impedance (connected to channel) | $100 \mathrm{M} \Omega$ |
| -3 dB Bandwidth | 400 MHz |
| Maximum input voltage | 1000 V RMS CAT II |
| Probe cable length | 1.2 m (3.9 ft) |
| Probe weight | Typically $67 \mathrm{~g}(2.4 \mathrm{oz})$ |
| Probe operating temperature range | $0^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(32{ }^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |
| Original manufacturer's part number | PMK PHV1000-1-45 |
|  |  |

Figure 1.13: Probe and probe accessories

Note The compensation range of the G903 probe does not match that of GN1610/GN1611/GN3210/GN3211 cards. For the limited bandwidth of GN1610/GN1611/GN3210/GN3211, this has no noticeable effects. When using the G903 probe in combination with this card select the sensor "G903_NoCapacitiveCheck" from the Perception Sensor Database.

## G904: Passive, Single-Ended Voltage Probe (Option, to be ordered separately)

To be used with single-ended amplifiers or with differential amplifiers in single-ended mode


Figure 1.14: Block diagram passive, single-ended voltage probe

| Isolation | Not supported |
| :---: | :---: |
| Capacitive compensation range | 10 to 50 pF |
| DC In-accuracy | 2\% |
| Divide factors | 100:1 |
| Probe impedance (connected to channel) | $50 \mathrm{M} \Omega$ |
| -3 dB Bandwidth | 300 MHz |
| Maximum input voltage | 2 kV RMS @ 50/60 Hz 3 kV DC |
| Probe cable length | 2 m (6.7 ft) |
| Probe weight | Typically $68 \mathrm{~g}(2.4 \mathrm{oz})$ |
| Probe operating temperature range | $0^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(32{ }^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |
| Original manufacturer's part number | PMK 117-901600 |



Figure 1.15: Probe and probe accessories

Note The compensation range of the G904 probe does not match that of GN1610/GN1611/GN3210/GN3211 cards. For the limited bandwidth of GN1610/GN1611/GN3210/GN3211, this has no noticeable effects. When using the G904 probe in combination with this card select the sensor "G904_NoCapacitiveCheck" from the Perception Sensor Database.

G906: Passive, Single-Ended Voltage Probe (Option, to be ordered separately)
To be used with single-ended amplifiers or with differential amplifiers in single-ended mode


Figure 1.16: Block diagram passive, single-ended voltage probe

| Isolation | Not supported |
| :---: | :---: |
| Capacitive compensation range | 10 to 50 pF |
| DC In-accuracy | 2\% |
| Divide factors | 1000:1 |
| Probe impedance (connected to channel) | $100 \mathrm{M} \Omega$ |
| -3 dB Bandwidth | 100 MHz |
| Maximum input voltage | 14 kV RMS @ 50/60 Hz, 20 kV DC |
| Probe cable length | Typically 3 m (9.8 ft) |
| Probe weight | Typically 465 g (16.4 oz) |
| Probe operating temperature range | $0^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(32^{\circ} \mathrm{F}\right.$ to $\left.122^{\circ} \mathrm{F}\right)$ |
| Original manufacturer's part number | PMK PHV 4002-3 |
|  | (11.2") |

Figure 1.17: Dimensions
To be used with single-ended amplifiers or with differential amplifiers in single-ended mode


Figure 1.18: Probe and probe accessories

Note The compensation range of the G906 probe does not match that of GN1610/GN1611/GN3210/GN3211 cards. For the limited bandwidth of GN1610/GN1611/GN3210/GN3211, this has no noticeable effects. When using the G906 probe in combination with this card select the sensor "G906_NoCapacitiveCheck" from the Perception Sensor Database.


Figure 1.19: Block diagram active, differential voltage probe

| Isolation | Not supported |  |
| :---: | :---: | :---: |
| Capacitive compensation range | Not required as this is an active output |  |
| DC In-accuracy | 2\% |  |
| Probe impedance | $4 \mathrm{M} \Omega$ for each input |  |
| - 3 dB Bandwidth | 25 MHz |  |
| Rise time | 14 ns |  |
| CMRR (typical) | -80 dB @ $50 \mathrm{~Hz},-60 \mathrm{~dB}$ @ 20 kHz |  |
| Output voltage | $\pm 7 \mathrm{~V}$ (50 k $\Omega$ load) |  |
| Output typical offset | $< \pm 5 \mathrm{mV}$ |  |
| Output typical noise | 0.7 mV RMS |  |
| Output source impedance | $50 \Omega$ |  |
| Divide factor | 20:1 | 200:1 |
| Maximum measuring voltage | 140 V RMS CAT III | 1000 V RMS CAT III |
| Common mode voltage | 1000 V RMS | 1000 V RMS |
| Maximum voltage on each input (Common mode + measurement voltage) | 1000 V RMS | 1000 V RMS |
| Probe power | 4 * AA cell battery or external power |  |
| External power source | Regulated voltage between 4.4 V DC and 12 V DC |  |
| Power usage | $\begin{aligned} & 60 \mathrm{~mA} @ 6 \mathrm{~V} \text { DC } \\ & 40 \mathrm{~mA} @ 9 \mathrm{~V} \text { DC } \end{aligned}$ |  |
| Probe cable length | Input leads $0.45 \mathrm{~m}(1.48 \mathrm{ft})$ <br> BNC output cable 0.95 m ( 3.12 ft ) |  |
| Probe weight | Typically 265 g (3.6 oz) |  |
| Probe operating temperature range | $-10^{\circ} \mathrm{C}$ to $+40{ }^{\circ} \mathrm{C}\left(14^{\circ} \mathrm{F}\right.$ to $\left.104{ }^{\circ} \mathrm{F}\right)$ |  |
| Original manufacturers part number | Probe Master Inc ${ }^{\text {TM }}, 4231-20 \mathrm{X} / 200 \mathrm{X}$ |  |



Figure 1.20: G909 Probe

## G912: AC/DC Current Clamp i30s (Option, to be ordered separately)

To be used with single-ended isolated or non-isolated amplifiers or with differential isolated or non-isolated amplifiers in single-ended mode


Figure 1.21: Dimensions
The i30s current clamp is based on Hall effect technology to measure both DC and AC current. The i30s current clamp may be used with recording instruments to measure the current accurately and non-intrusively.
Electrical specifications

| Current range | 30 mA to $30 \mathrm{~A} \mathrm{DC}$,30 mA to 20 ARMS |
| :---: | :---: |
| In-accuracy | $\pm 1 \%$ of reading $\pm 2 \mathrm{~mA}$ (at $+25^{\circ} \mathrm{C}, 77^{\circ} \mathrm{F}$ ) |
| Phase shift | < 2 degrees when using frequencies below 1 kHz |
| Crest factor | 1.4 |
| Conductor position sensitivity | $\pm 1 \%$ relative to center reading |
| Output sensitivity | $100 \mathrm{mV} / \mathrm{A}$ |
| Bandwidth | DC to -0.5dB @ 100 kHz |
| Load impedance | $>100 \mathrm{k} \Omega$ |
| Temperature drift | $\pm 0.01 \%$ of reading ${ }^{\circ} \mathrm{C}$ |
| Isolation/Working voltage | 300 V RMS CAT III, pollution degree 2, frequencies below 1 kHz |
| General specifications |  |
| Power supply | 9 V Alkaline, MN1604/PP3, 30 hours, low battery indicator |
| Maximum conductor diameter | 19 mm (0.75") |
| Output connection | Safety BNC connector |
| Probe cable length | 2 m (6.5 ft) |
| Probe dimensions (HxWxD) | $183 \times 71 \times 25 \mathrm{~mm}$ ( 7.20 " $\times 2.80 " \times 0.99$ ") |
| Probe weight | Typically $250 \mathrm{~g}(8.8 \mathrm{oz})$ |
| Probe operating temperature range | $0^{\circ} \mathrm{C}$ to $+50{ }^{\circ} \mathrm{C}\left(32{ }^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |
| Original manufacturer's part number | Fluke i30s AC/DC Current Clamp |



Figure 1.22: AC/DC Current Clamp i30s

## G913: AC Current Clamp SR661 (Option, to be ordered separately)

To be used with single-ended isolated or non-isolated amplifiers or with differential isolated or non-isolated amplifiers in single-ended mode


Figure 1.23: Dimensions
Built to the highest safety standards, including CE compliance and UL approval in the USA and Canada. Has excellent transformation, low phase shifts and a broad frequency response. Permits the current to be measured accurately for power and power quality applications.

Electrical specifications

| Current range | 0.1 A to 1200 A RMS, can be manually selecte |  |
| :---: | :---: | :---: |
| Selected current range | 10 A | 100 A |
| Measurement range | 0.1 to 12 A | 0.1 to 120 A |
| Output sensitivity | $100 \mathrm{mV} / \mathrm{A}$ | $10 \mathrm{mV} / \mathrm{A}$ |
| In-accuracy | $\pm 3 \% \pm 10 \mathrm{mV}$ | $\pm 2 \% \pm 5 \mathrm{mV}$ |
| Phase shift | $\leq 15$ degrees | $\leq 15$ degrees |
| Maximum overload | 12 A , continuous | 120 A , continuo |
| Bandwidth | 1 Hz to -3 dB @ 100 kHz |  |
| Load impedance | $1 \mathrm{M} \Omega$ @ 47 pF |  |
| Isolation/Working voltage | 600 V RMS CAT III, pollution degree 2 |  |
| General specifications |  |  |
| Maximum conductor diameter | 52 mm (2.25") |  |
| Output connection | Safety BNC connector |  |
| Probe cable length | 2 m (6.5 ft) |  |
| Probe dimensions (HxWxD) | $216 \times 111 \times 45 \mathrm{~mm}$ (8.50" $\left.\times 4.37^{\prime \prime} \times 1.77^{\prime \prime}\right)$ |  |
| Probe weight | Typically $550 \mathrm{~g}(1.21 \mathrm{lbs})$ |  |
| Probe operating temperature range | $-10^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(14^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |  |
| Original manufacturer's part number | AEMC SR661 AC Current Clamp |  |
|  |  |  |

Figure 1.24: SR661 AC Current Clamp

G914: AC Current Clamp M1V-20-2 (Option, to be ordered separately)
To be used with single-ended isolated or non-isolated amplifiers or with differential isolated or non-isolated amplifiers in single-ended mode


Figure 1.25: Dimensions

| AC current micro clamp, compliant with IEC standard 348 CLASS II 600 V |  |
| :---: | :---: |
| Electrical specifications |  |
| Current range | 50 mA to 20 A RMS |
| In-accuracy | $\pm 1 \%$ |
| Output sensitivity | $100 \mathrm{mV} / \mathrm{A}$ |
| Bandwidth | -3 dB @ 30 Hz to $100 \mathrm{kHz}, 3 \%$ @ 40 Hz to 2 kHz |
| Load impedance | $>30 \mathrm{k} \Omega$ |
| Isolation/Working voltage | 640 V RMS |
| General specifications |  |
| Maximum conductor diameter | 15 mm (0.59") |
| Output connection | Metal BNC |
| Probe cable length | 2 m (6.5 ft) |
| Probe dimensions (HxWxD) | $97 \times 43 \times 23 \mathrm{~mm}$ (3.82" $\times 1.69{ }^{\prime \prime} \times 0.91$ ") |
| Probe weight | Typically $114 \mathrm{~g}(0.25 \mathrm{lb})$ |
| Probe operating temperature range | $-10^{\circ} \mathrm{C}$ to $+50^{\circ} \mathrm{C}\left(14^{\circ} \mathrm{F}\right.$ to $\left.122{ }^{\circ} \mathrm{F}\right)$ |
| Original manufacturer's part number | AYA instruments M1V-20-2 |



Figure 1.26: M1V-20-2

## Environmental Specifications

| Temperature Range |  |
| :---: | :---: |
| Operational | $0^{\circ} \mathrm{C}$ to $+40{ }^{\circ} \mathrm{C}\left(+32{ }^{\circ} \mathrm{F}\right.$ to $\left.+104{ }^{\circ} \mathrm{F}\right)$ |
| Non-operational (Storage) | $-25^{\circ} \mathrm{C}$ to $+70{ }^{\circ} \mathrm{C}\left(-13{ }^{\circ} \mathrm{F}\right.$ to $\left.+158{ }^{\circ} \mathrm{F}\right)$ |
| Thermal protection | Automatic thermal shutdown at $85^{\circ} \mathrm{C}\left(+185^{\circ} \mathrm{F}\right)$ internal temperature <br> User warning notifications at $75^{\circ} \mathrm{C}\left(+167^{\circ} \mathrm{F}\right)$ (Supported by Perception V6.30 or higher) |
| Relative humidity | 0\% to 80\%; non-condensing; operational |
| Protection class | IP20 |
| Altitude | Maximum 2000 m (6562 ft) above sea level; operational |
| Shock: IEC 60068-2-27 |  |
| Operational | Half-sine $10 \mathrm{~g} / 11 \mathrm{~ms}$; 3-axis, 1000 shocks in positive and negative direction |
| Non-operational | Half-sine $25 \mathrm{~g} / 6 \mathrm{~ms}$; 3-axis, 3 shocks in positive and negative direction |
| Vibration: IEC 60068-2-64 |  |
| Operational | 1 g RMS, $1 / 2 \mathrm{~h}$; 3-axis, random 5 to 500 Hz |
| Non-operational | $2 \mathrm{~g} \mathrm{RMS}, 1 \mathrm{~h} ; 3$-axis, random 5 to 500 Hz |
| Operational Environmental Tests |  |
| Cold test IEC 60068-2-1 Test Ad | $-5^{\circ} \mathrm{C}\left(+23^{\circ} \mathrm{F}\right)$ for 2 hours |
| Dry heat test IEC 60068-2-2 Test Bd | $+40^{\circ} \mathrm{C}\left(+104{ }^{\circ} \mathrm{F}\right)$ for 2 hours |
| Damp heat test IEC 60068-2-3 Test Ca | $+40{ }^{\circ} \mathrm{C}\left(+104{ }^{\circ} \mathrm{F}\right)$, humidity $>93 \% \mathrm{RH}$ for 4 days |
| Non-Operational (Storage) Environmental Tests |  |
| Cold test IEC 60068-2-1 Test Ab | $-25^{\circ} \mathrm{C}\left(-13^{\circ} \mathrm{F}\right)$ for 72 hours |
| Dry heat test IEC 60068-2-2 Test Bb | $+70^{\circ} \mathrm{C}\left(+158{ }^{\circ} \mathrm{F}\right)$ humidity $<50 \%$ RH for 96 hours |
| Change of temperature test IEC 60068-2-14 Test Na | $-25^{\circ} \mathrm{C} \text { to }+70^{\circ} \mathrm{C}\left(-13^{\circ} \mathrm{F} \text { to }+158^{\circ} \mathrm{F}\right)$ <br> 5 cycles, rate 2 to 3 minutes, dwell time 3 hours |
| Damp heat cyclic test IEC 60068-2-30 Test Db variant 1 | $+25^{\circ} \mathrm{C} /+40^{\circ} \mathrm{C}\left(+77^{\circ} \mathrm{F} /+104^{\circ} \mathrm{F}\right) \text {, humidity }>95 / 90 \% \mathrm{RH}$ 6 cycles, cycle duration 24 hours |

## Harmonized Standards for CE Compliance, According to the Following Directives

Low Voltage Directive (LVD): 2006/95/EC
ElectroMagnetic Compatibility Directive (EMC): 2004/108/EC

| Electrical Safety |  |
| :---: | :---: |
| EN 61010-1 (2010) | Safety requirements for electrical equipment for measurement, control, and laboratory use - General requirements |
| EN 61010-2-030 (2010) | Particular requirements for testing and measuring circuits |
| Electromagnetic Compatibility |  |
| EN 61326-1 (2013) | Electrical equipment for measurement, control and laboratory use - EMC requirements - Part 1: General requirements |
| Emission |  |
| EN 55011 | Industrial, scientific and medical equipment - Radio-frequency disturbance characteristics - Limits and methods of measurement <br> Conducted disturbance: class B; Radiated disturbance: class A |
| EN 61000-3-2 | Limits for harmonic current emissions: class D |
| EN 61000-3-3 | Limitation of voltage changes, voltage fluctuations and flicker in public low voltage supply systems |
| Immunity |  |
| EN 61000-4-2 | Electrostatic discharge immunity test (ESD); contact discharge $\pm 4 \mathrm{kV} /$ air discharge $\pm 8 \mathrm{kV}$ : performance criteria B |
| EN 61000-4-3 | Radiated, radio-frequency, electromagnetic field immunity test; 80 MHz to 2.7 GHz using $10 \mathrm{~V} / \mathrm{m}, 1000 \mathrm{~Hz} \mathrm{AM}$ : performance criteria A |
| EN 61000-4-4 | Electrical fast transient/burst immunity test <br> Mains $\pm 2 \mathrm{kV}$ using coupling network. Channel $\pm 2 \mathrm{kV}$ using capacitive clamp: performance criteria B |
| EN 61000-4-5 | Surge immunity test <br> Mains $\pm 0.5 \mathrm{kV} / \pm 1 \mathrm{kV}$ Line-Line and $\pm 0.5 \mathrm{kV} / \pm 1 \mathrm{kV} / \pm 2 \mathrm{kV}$ Line-earth Channel $\pm 0.5 \mathrm{kV} / \pm 1 \mathrm{kV}$ using coupling network: performance criteria B |
| EN 61000-4-6 | Immunity to conducted disturbances, induced by radio-frequency fields 150 kHz to $80 \mathrm{MHz}, 1000 \mathrm{~Hz}$ AM; 10 V RMS @ mains, 3 V RMS @ channel, both using clamp: performance criteria A |
| EN 61000-4-11 | Voltage dips, short interruptions and voltage variations immunity tests Dips: performance criteria A; Interruptions: performance criteria C |


| Ordering Information ${ }^{(1)}$ |  |  |  |
| :---: | :---: | :---: | :---: |
| Article |  | Description | Order No. |
| HiSpeed 100M |  | 4 channels, 14 bit, $100 \mathrm{MS} / \mathrm{s}, \pm 20 \mathrm{mV}$ to $\pm 100 \mathrm{~V}$ input range, 1800 MB RAM ( $225 \mathrm{MS} /$ channel), balanced differential input, two metal BNCs per channel | 1-GN412-2 |

(1) All GEN series systems are intended for exclusive professional and industrial use.

| Options, to be ordered separately |  |  |  |
| :---: | :---: | :---: | :---: |
| Article |  | Description | Order No. |
| 2 Gbyte Memory Upgrade |  | 2 Gbyte memory upgrade for $100 \mathrm{MS} / \mathrm{s}$ digitizers and fiber receiver cards with 1 Gbyte memory only (factory installed upgrade, includes recalibration) | 1-G030-2 |


| Voltage Probes (Options, to be ordered separately) |  |  |  |
| :---: | :---: | :---: | :---: |
| Article |  | Description | Order No. |
| Passive, SE probe 10:1, 200 MHz , $10 \mathrm{M} \Omega, 1.2 \mathrm{~m}$ |  | Passive, single-ended voltage probe. Has a capacitive compensation range from 7 to 75 pF . Divide factors of $1: 1$ and 10:1 can be selected. When divide factor 10:1 is selected, the bandwidth is $-3 \mathrm{~dB} @ 200 \mathrm{MHz}$, maximum input voltage is 300 V RMS CAT II, maximum DC In-accuracy is $2 \%$, and the probe connected to a channel has an input impedance of $10 \mathrm{M} \Omega$. Probe cable length is $1.2 \mathrm{~m}(3.9 \mathrm{ft})$. | 1-G901-2 |
| Passive, SE probe 10:1, 100 MHz , $10 \mathrm{M} \Omega, 3 \mathrm{~m}$ |  | Passive, single-ended voltage probe. Has a capacitive compensation range from 7 to 75 pF . Divide factors of 1:1 and 10:1 can be selected. When divide factor 10:1 is selected, the bandwidth is $-3 \mathrm{~dB} @ 100 \mathrm{MHz}$, maximum input voltage is 300 V RMS CAT II, maximum DC In-accuracy is $2 \%$, and the probe connected to a channel has an input impedance of $10 \mathrm{M} \Omega$. Probe cable length is $3 \mathrm{~m}(9.8 \mathrm{ft})$. | 1-G902-2 |
| Passive, SE isolated probe, 100:1, 400 MHz , $100 \mathrm{M} \Omega$ |  | Passive, single-ended isolated voltage probe. Has a capacitive compensation range from 7 to 45 pF . The divide factor is $100: 1$, bandwidth is $-3 \mathrm{~dB} @ 400 \mathrm{MHz}$, maximum input voltage is 1000 V RMS CAT II, maximum DC In-accuracy is $2 \%$, and the probe connected to a channel has an input impedance of $100 \mathrm{M} \Omega$. Probe cable length is $1.2 \mathrm{~m}(3.9 \mathrm{ft})$. | 1-G903-2 |
| Passive, SE isolated probe, 100:1, 300 MHz , $50 \mathrm{M} \Omega$ |  | Passive, single-ended isolated voltage probe. Has a capacitive compensation range from 10 to 50 pF . The divide factor is $10: 1$, bandwidth is $-3 \mathrm{~dB} @ 300 \mathrm{MHz}$, maximum input voltage is 2 kV RMS, maximum DC In-accuracy is $2 \%$, and the probe connected to a channel has an input impedance of $50 \mathrm{M} \Omega$. Probe cable length is $2 \mathrm{~m}(3.9 \mathrm{ft})$. | 1-G904-2 |
| Passive, SE isolated probe, 1000:1, 100 MHz , $100 \mathrm{M} \Omega$ |  | Passive, single-ended isolated voltage probe. Has a capacitive compensation range from 10 to 50 pF . The divide factor is $10: 1$, bandwidth is $-3 \mathrm{~dB} @ 100 \mathrm{MHz}$, maximum input voltage is 14 kV RMS @ 50/60 Hz, maximum DC In-accuracy is $2 \%$, and the probe connected to a channel has an input impedance of $100 \mathrm{M} \Omega$. Probe cable length is $3 \mathrm{~m}(9.8 \mathrm{ft})$. | 1-G906-2 |
| Active, DIFF probe, 200:1, 25 MHz, $4 \mathrm{M} \Omega$ |  | Active, differential voltage probe. Supported by every input channel due to the active output. Divide factors of 20:1 and 200:1 can be manually selected. Supported bandwidth -3 dB @ 25 MHz . Maximum input voltage and common mode voltage both are 1000 V RMS. Maximum DC In-accuracy is $2 \%$, and the probe has an input impedance of $4 \mathrm{M} \Omega$ on each input. Probe coax cable length is 0.95 m ( 3.12 ft ). | 1-G909-2 |



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